CSP-30ES-013

With the addition of the CSP-30ES-013 high performance Radio Frequency probe, ECT adds to its industry proven high speed test interface portfolio. The probe incorporates several innovative features that result in superior performance and ease of use. The CSP-30ES-013 was specifically designed to mate with SMA connectors. With a bandwidth in excess of 20 GHz @ -1dB the CSP-30ES-013 offers outstanding signal integrity and measurement capability.

The CSP-30ES-013 provides spring loaded compliance for both the center signal probe and outer housing that provides ground contact. The CSP-30ES-013 features an easy to replace center conductor probe. The knurl housing feature provides for easy and reliable press fit mounting.

The CSP-30ES-013 coaxial probe provides instrumentation-quality interface for broadband R.F. measurements in excess of 20 GHz. With the CSP-30ES-013 R.F. circuit design, impedance characterization measurements can be performed in both high volume testing or engineering lab environments. Accurate and repeatable small signal and R.F. power (50 Watts) measurements provide consistent and repeatable results.

CSP Benefits Summary

- Probe mates to standard SMA connectors
- Easy to replace inner probe: SPL-30E-030
- Articulated contact allows for targeting errors
- Ideal for high volume production or engineering lab test
- Incorporates spring probes in an open architecture format
- Proven RF measurements in excess of 20 GHz
- Consistent 50 Ohm impedance
- Rugged design for inline applications

CSP-30ES-013 Probe mating with an SMA connector

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CSP-30ES-013

Mechanical
Recommended Travel: .100 (2.54)
Recommended Travel inner conductor: .040 (1.02)
Recommended Travel outer conductor: .100 (2.54)
Full Travel: .200 (5.08)
Operating Temperature: 85°C
Connection (instrument side): SMA Connector, 1/4 -36UNS-2A

Spring Force in oz. (grams)

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<tr>
<th>Order Code</th>
<th>Preload</th>
<th>Rec. Travel</th>
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<tr>
<td>Standard</td>
<td>CSP-30ES-013</td>
<td>3.06 (86.7)</td>
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Electrical (Static Conditions)
Nominal Impedance: 50 Ohms
Average Probe Resistance: <50 mOhms
Bandwidth @ -1 dB: > 20 GHz

Materials and Finishes
Housing: Brass, Gold plated
Dielectric: Teflon
Spring: Stainless Steel, Nickel Plated

Mounting
Hole diameter: Ø.297 (7.54)

Replaceable Probes
Order Number (CSP-30ES-013): SPL-30E-030

Applications
Designed for use in interconnect applications where signal integrity is required, such as accessing
high frequency RF connectors on circuit boards. Can also be used as R.F. mating connector.

Replaceable probe: SPL-30E-030

Dimensions in inches (mm)

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